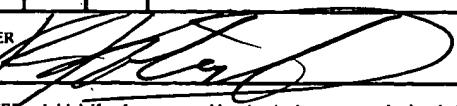


Form PTO-1440		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-2524	SERIAL NO. 10/803,264		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Warren M. Parryworth et al.			
				FILING DATE March 17, 2004	GROUP 2529		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RK</i>	AA	5580827	12/03/96	<i>Akamine</i>	437	225	<i>T</i>
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Paragraph Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>RK</i>				DATE CONSIDERED <i>11-22-04</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with each communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M112-2524	SERIAL NO. 10803244		
LIST OF ART CITED BY APPLICANT (Use reverse sheets if necessary)				APPLICANT Warren M. Farmarath et al.			
				FILING DATE March 17, 2004	GROUP 2829		
U.S. PATENT DOCUMENTS							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>Re</i>	AA	6426638	07/30/73	Di Stefano	324	754	-
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Page, Etc.)							
	AR						
	AS						
	AT						
EXAMINER: <i>[Signature]</i>				DATE CONSIDERED: <i>11-22-04</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and note consideration. Include copy of this form with next communication to applicant.							

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>					ATTY. DOCKET NO. MI22-2524	SERIAL NO. Filed Herewith		
					APPLICANT Warren M. Farnworth et al.			
					FILING DATE Filed Herewith	GROUP <i>3829</i>		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>PK</i>	AA	3,412,456	11/68	Ebisawa				
	AB	3,469,019	9/69	Reinmann				
	AC	4,105,970	8/78	Katz				
	AD	4,141,055	2/79	Berry et al.				
	AE	4,182,781	1/80	Hooper et al.				
	AF	4,189,825	2/80	Robillard et al.				
	AG	4,312,117	1/82	Robillard et al.				
	AH	4,315,984	2/82	Okazaki et al.				
	AI	4,417,206	11/83	Stowers				
	AJ	4,499,656	2/85	Fabian et al.				
	AK	4,585,991	4/86	Reid et al.				
<i>PK</i>	AL	4,881,118	11/89	Niwayama et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>PK</i>	AM	53171	03/91	Japan				
<i>PK</i>	AN	108350	05/91	Japan				
<i>PK</i>	AO	329314	08/89	European (EPO)				
<i>PK</i>	AP	5714838	09/82	Japan				
<i>PK</i>	AQ	2-5540	01/90	Japan				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
<i>PK</i>	AR	Moto's Nakano "A Probe for Testing Semiconductor Integrated Circuits and a Test Method Using Said Probe." 25 March, 1991						
		Japanese Patent Office Disclosure No. Hei 3-69131, Filing No. Hei 1-205301, Filing Date August 8, 1989						
	AS							
	AT							
EXAMINER <i>PK</i>			DATE CONSIDERED <i>11-22-04</i>					
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					ATTY. DOCKET NO. MI22-2524	SERIAL NO. Filed Herewith	
					APPLICANT Warren M. Farnworth et al.		
					FILING DATE Filed Herewith	GROUP 2829	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RK</i>	AU	4,924,589	5/90	Leedy	7		
	AV	4,929,999	5/90	Hoebrechts et al.			
	AW	4,937,653	6/90	Blonder et al.			
	AX	4,952,272	8/90	Okino et al.			
	AY	4,963,225	10/90	Lehman-Lerner			
	AZ	5,420,520	5/93	Anschel et al.			
	BA	5,014,161	5/91	Lee et al.			
	BB	5,032,541	7/91	Sakamoto et al.			
	BC	5,045,780	9/91	Swart			
	BD	5,072,116	12/91	Kawade et al.			
	BE	5,103,557	4/92	Leedy			
<i>↓</i>	BF	5,137,461	8/92	Bindra et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
<i>RK</i>	BG	2232946	09/90	Japan	—	—	—
<i>RK</i>	BH	410446	01/92	Japan	—	—	—
/	BI						
/	BJ						
	BK						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	BL						
	BM						
	BN						
				DATE CONSIDERED <i>11-22-04</i>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-2524SERIAL NO.
Filed HerewithLIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Warren M. Farnworth et al.FILING DATE
Filed HerewithGROUP
2839

U.S. PATENT DOCUMENTS

*Examiner's Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RK</i>	BO	5,177,438	1/93	Littlebury et al.			
	BP	5,177,439	1/93	Liu et al.			
	BQ	5,196,251	3/93	Bakhru et al.			
	BR	5,206,585	4/93	Chang et al.			
	BS	5,235,140	8/93	Reeke et al.			
	BT	5,239,260	8/93	Widder et al.			
	BU	5,245,135	9/93	Schreiber et al.			
	BV	5,262,718	11/93	Svendsen et al.			
	BW	5,307,561	5/94	Feigenbaum et al.			
	BX	5,323,035	6/97	Leedy			
	BY	5,326,428	7/94	Farnworth et al.			
<i>V</i>	BZ	5,334,804	8/94	Love et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
CA							
CB							
CC							
CD							
CE							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

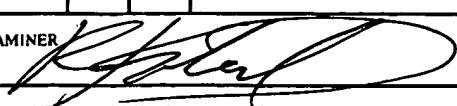
	CF		
	CG		
	CH		

EXAMINER

DATE CONSIDERED

11-22-04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				ATTY. DOCKET NO. M122-2524		SERIAL NO. Filed Herewith	
				APPLICANT Warren M. Farnworth et al.			
				FILING DATE Filed Herewith		GROUP <i>2839</i>	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>OK</i>	CI	5,353,195	10/94	Fillion et al.			
	CJ	5,367,253	11/94	Wood et al.			
	CK	5,402,077	03/95	Agahdel et al.			
	CL	5,419,807	05/95	Akram et al.			
	CM	5,431,328	07/95	Chang et al.			
	CN	5,478,779	12/95	Akram			
	CO	5,468,917	11/95	Brodsky et al.			
	CP	5,471,151	11/95	DiFrancesco			
	CQ	5,477,087	12/95	Kwakita et al.			
	CR	5,523,697	06/96	Farnworth et al.			
	CS	5,541,525	07/96	Wood et al.			
<i>OK</i>	CT	5,559,444	09/93	Farnworth et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	CU						
	CV						
	CW						
	CX						
	CY						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	CZ						
	DA						
	DB						
EXAMINER <i>R. K. S.</i> 				DATE CONSIDERED <i>11-22-04</i>			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2524	SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Warren M. Farnworth et al.					
		FILING DATE Filed Herewith	GROUP <i>2839</i>				
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class Subclass Filing Date If Appropriate		
<i>KL</i>	DC	5,625,297	04/97	Amaudov et al.			
	DD	5,716,218	02/98	Farnworth et al.			
	DE	5,790,337	08/98	Schreiber et al.			
	DF	5,831,832	11/98	Gillette et al.			
	DG	5,849,633	12/98	Akram			
	DH	5,869,787	02/99	Akram			
	DI	6,002,266	12/99	Briggs et al.			
	DJ	6,093,643	07/00	Akram			
	DK	4,566,184	01/86	Higgins et al..			
	DL	5,838,160	11/17/1998	Bexman et al.			
	DM	4,571,540	2/18/1986	Stowers et al.			
<i>▼</i>	DN	4,116,523	09/26/78	Coberly et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class Subclass	Translation	
						Yes	No
	DO						
	DP						
	DQ						
	DR						
	DS						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	DT						
	DU						
	DV						
EXAMINER <i>[Signature]</i>		DATE CONSIDERED <i>11-22-04</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							